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Decision and Control, 2001. Proceedings of the 40th IEEE Conference on , Vol 3 , 4-7 Dec. 2001

Pages:2827 - 2832 vol.3

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Particle Accelerator Conference, 1989. 'Accelerator Science and Technology', Proceedings of the 1989 IEEE , 20-23 March 1989

Pages:1648 - 1650 vol.3

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3 **Innovative aspects of the SDL control system**

Graves, W.S.; Feng, S.K.; Pearson, P.S.; Smith, J.D.;

Particle Accelerator Conference, 1997. Proceedings of the 1997 , Volume: 2 , May 1997

Pages:2437 - 2439 vol.2

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4 **Developments in 'standard' test gear**

Erskine, G.;

Instrumentation in Electronic Product Manufacture, IEE Colloquium on , 5 May

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